



# Electron Trains in LXe TPCs

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# XENON1T



<https://phys.org/news/2017-05-xenon1t-sensitive-detector-earth-wimp.html>

DMSS July 2018

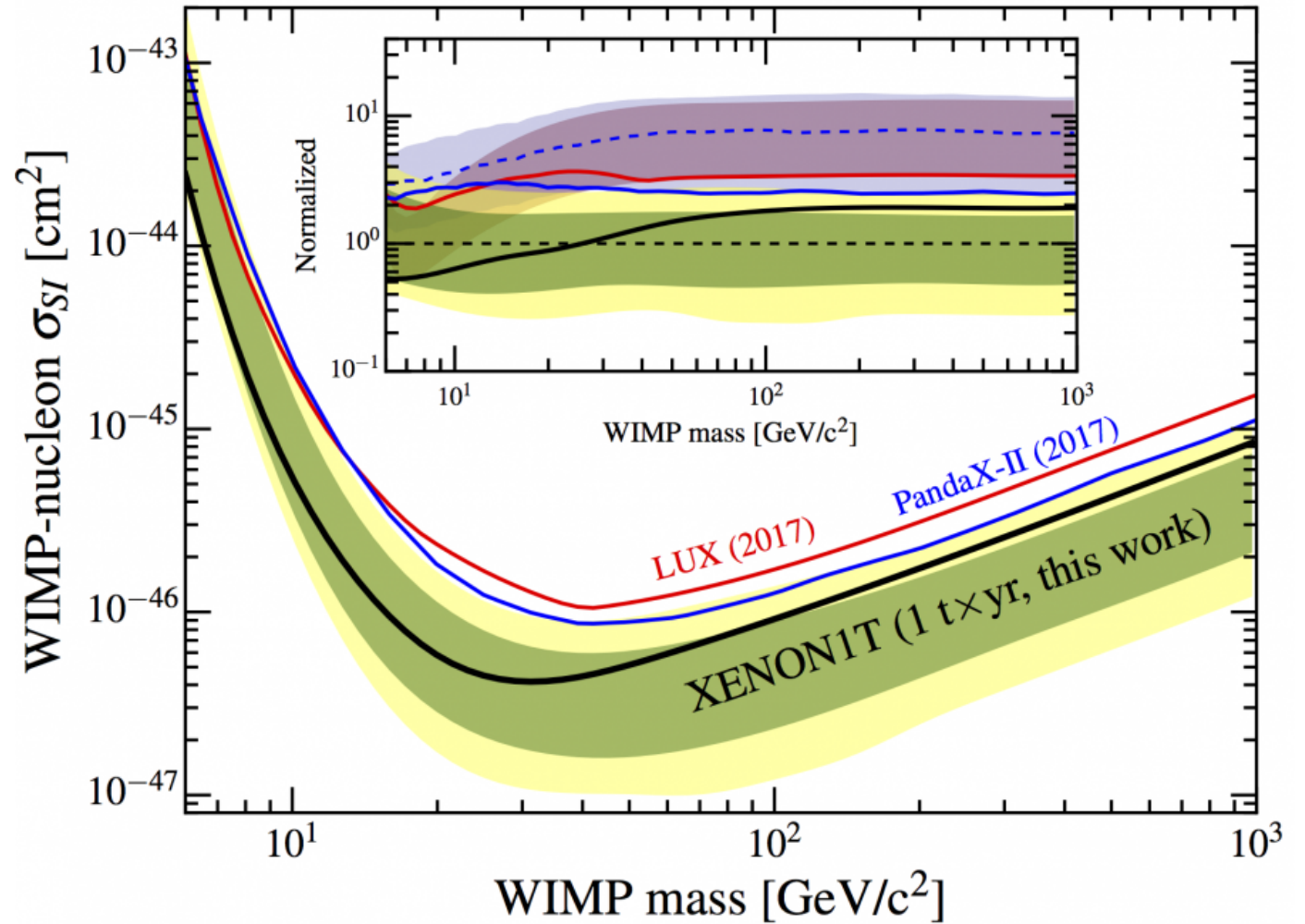
Amanda Depoian



# XENON1T recent results

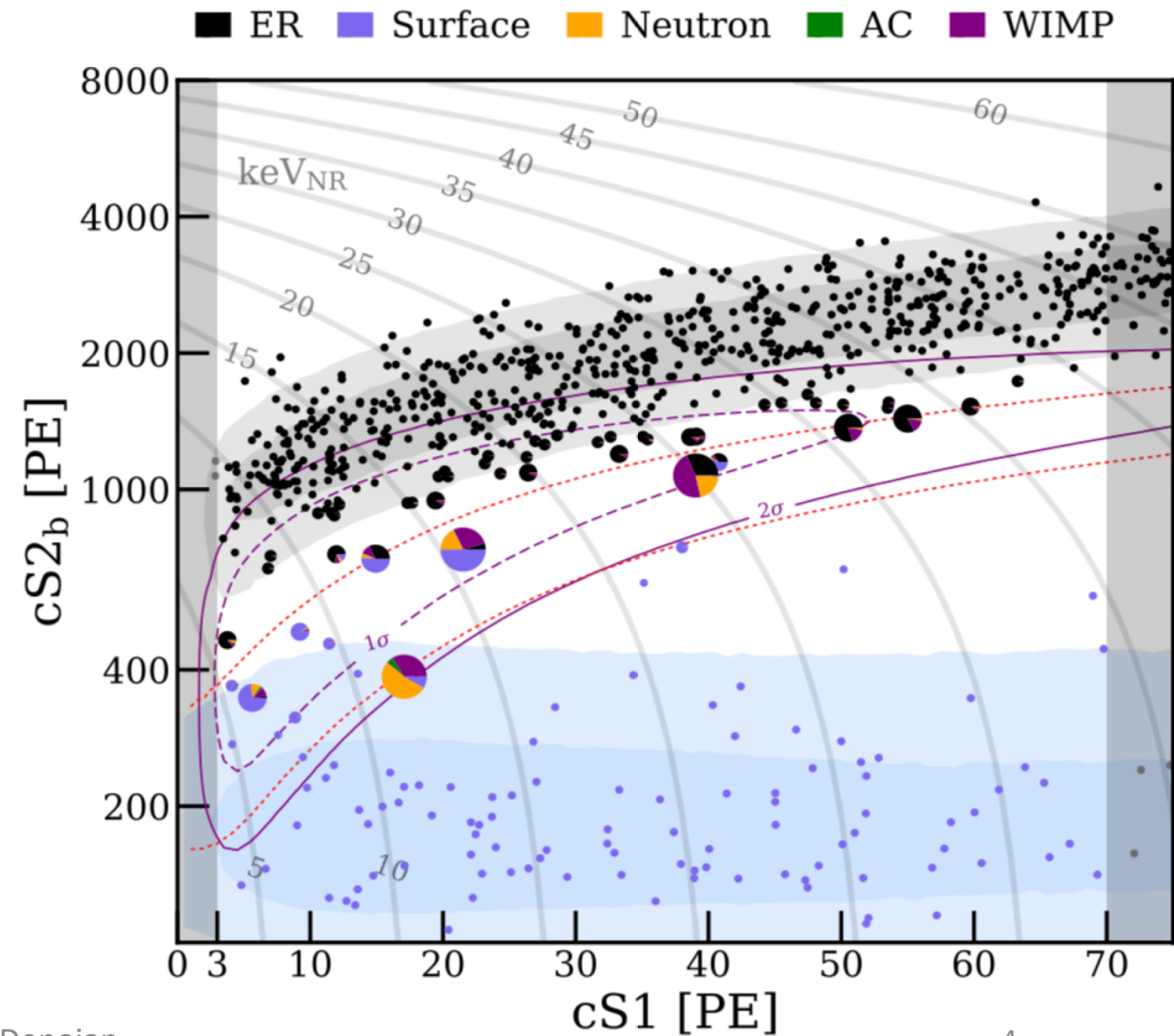
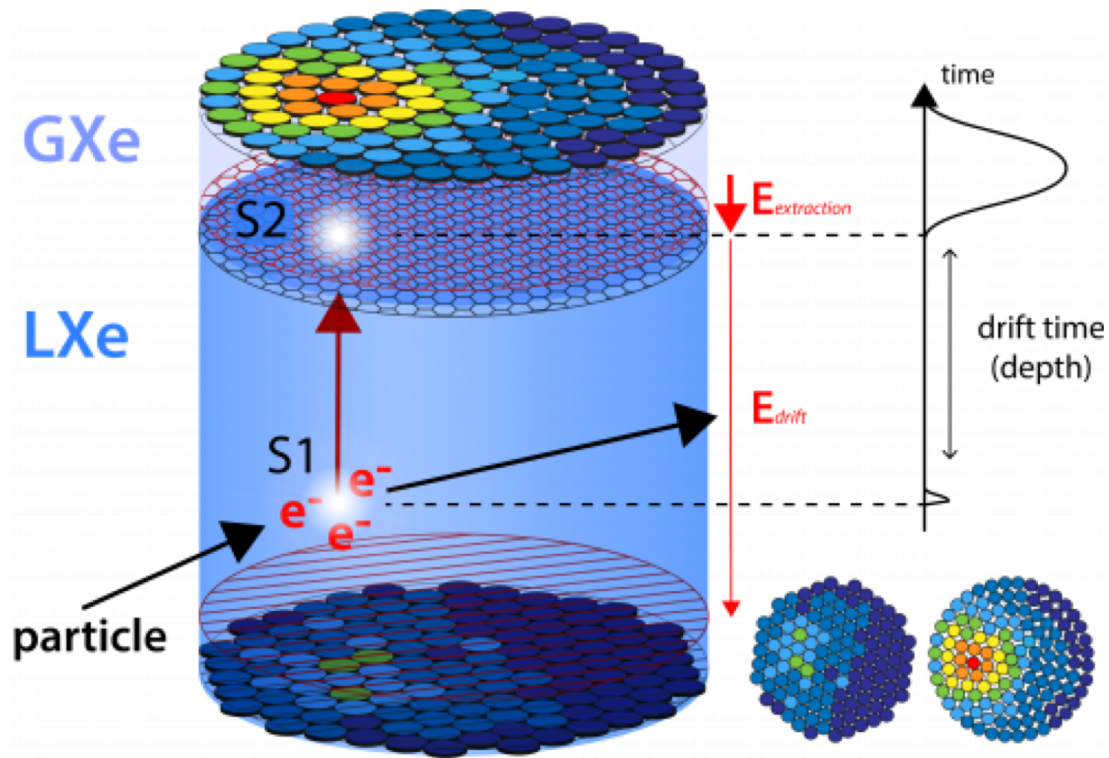
$$\sigma_{SI} < 4.1 \times 10^{-47} \text{ cm}^2$$

at  $30 \text{ GeV}/c^2$

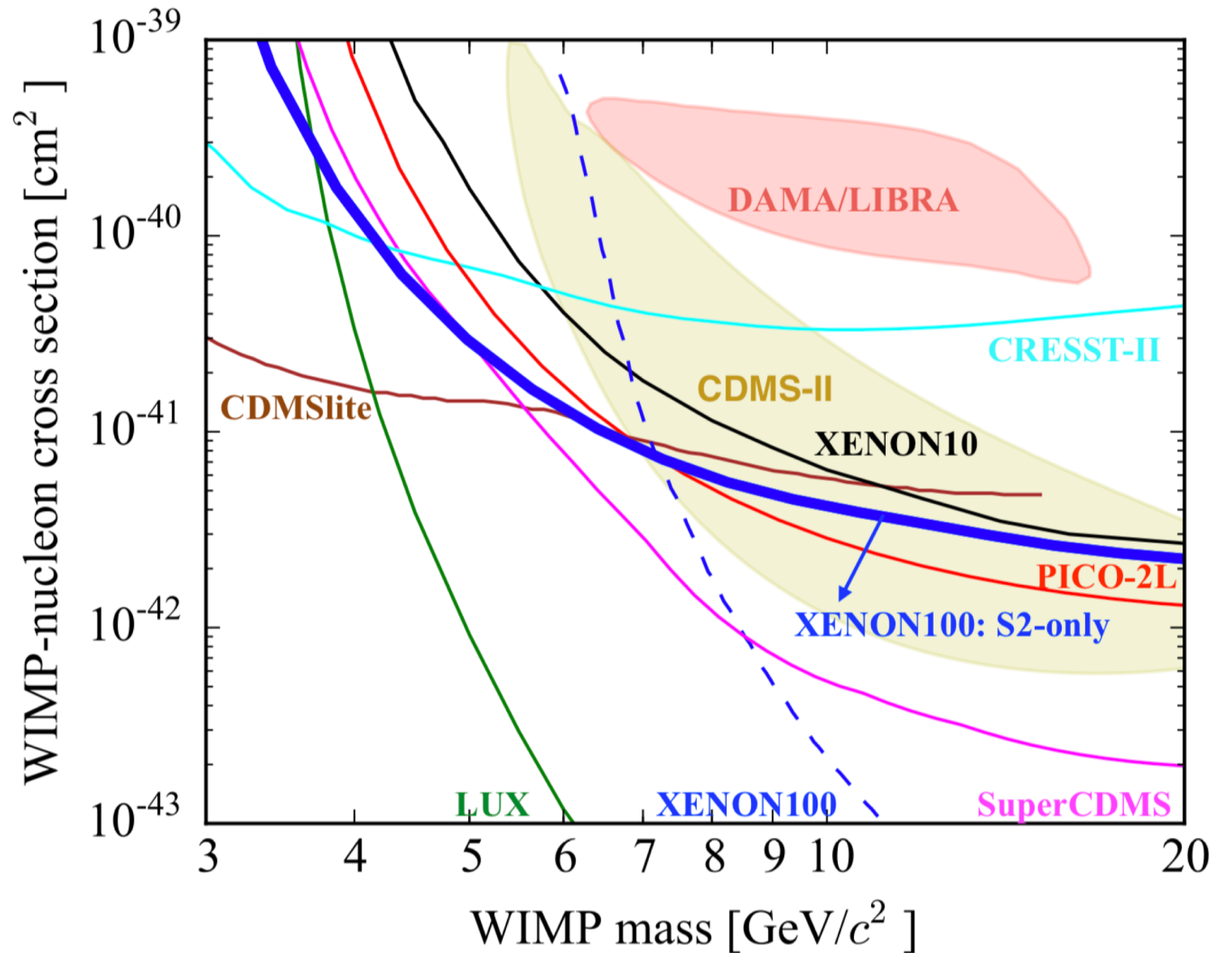


<https://arxiv.org/pdf/1805.12562.pdf>

# Probing lower S2 energies

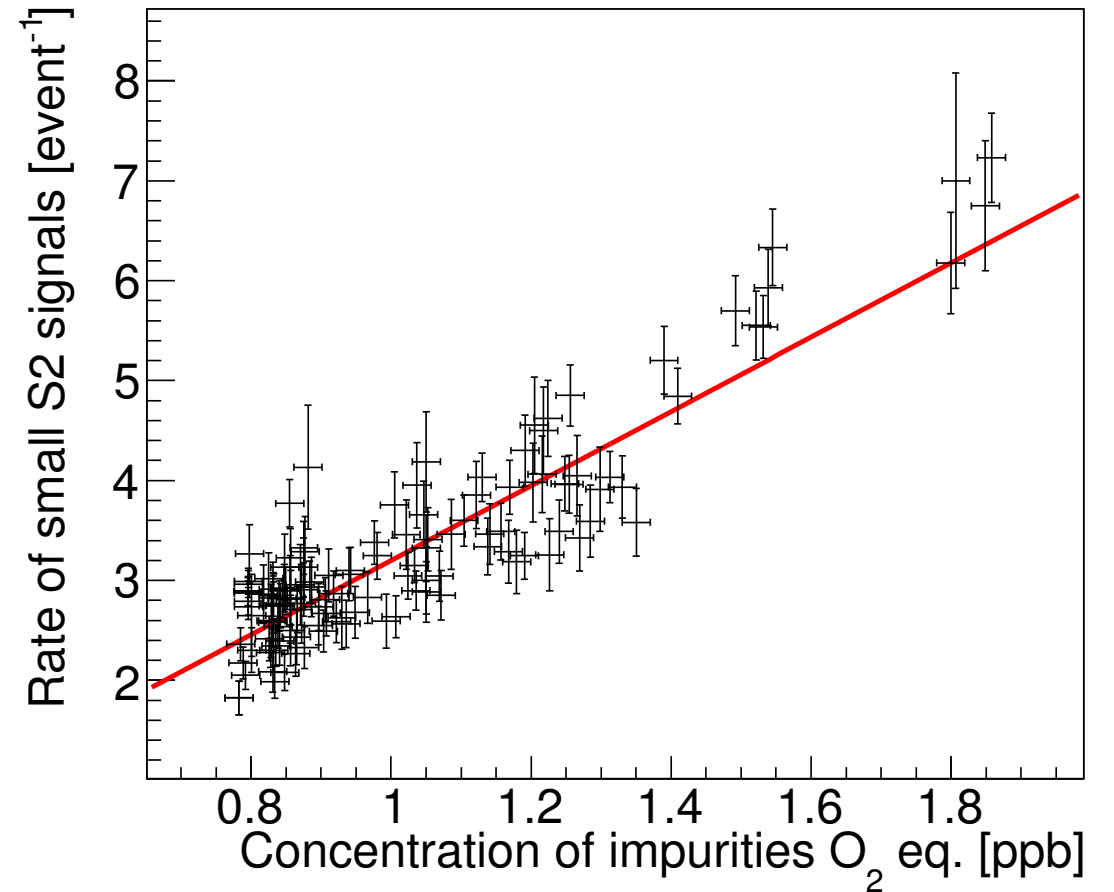
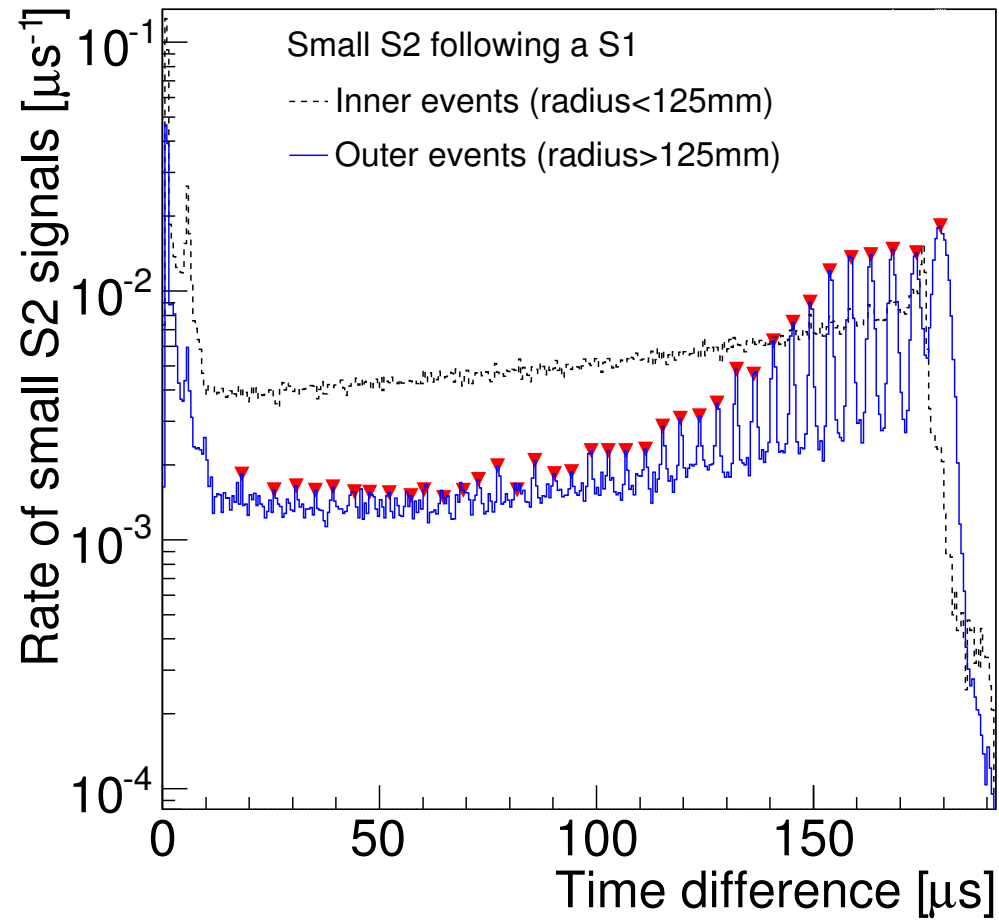


Hitting a wall



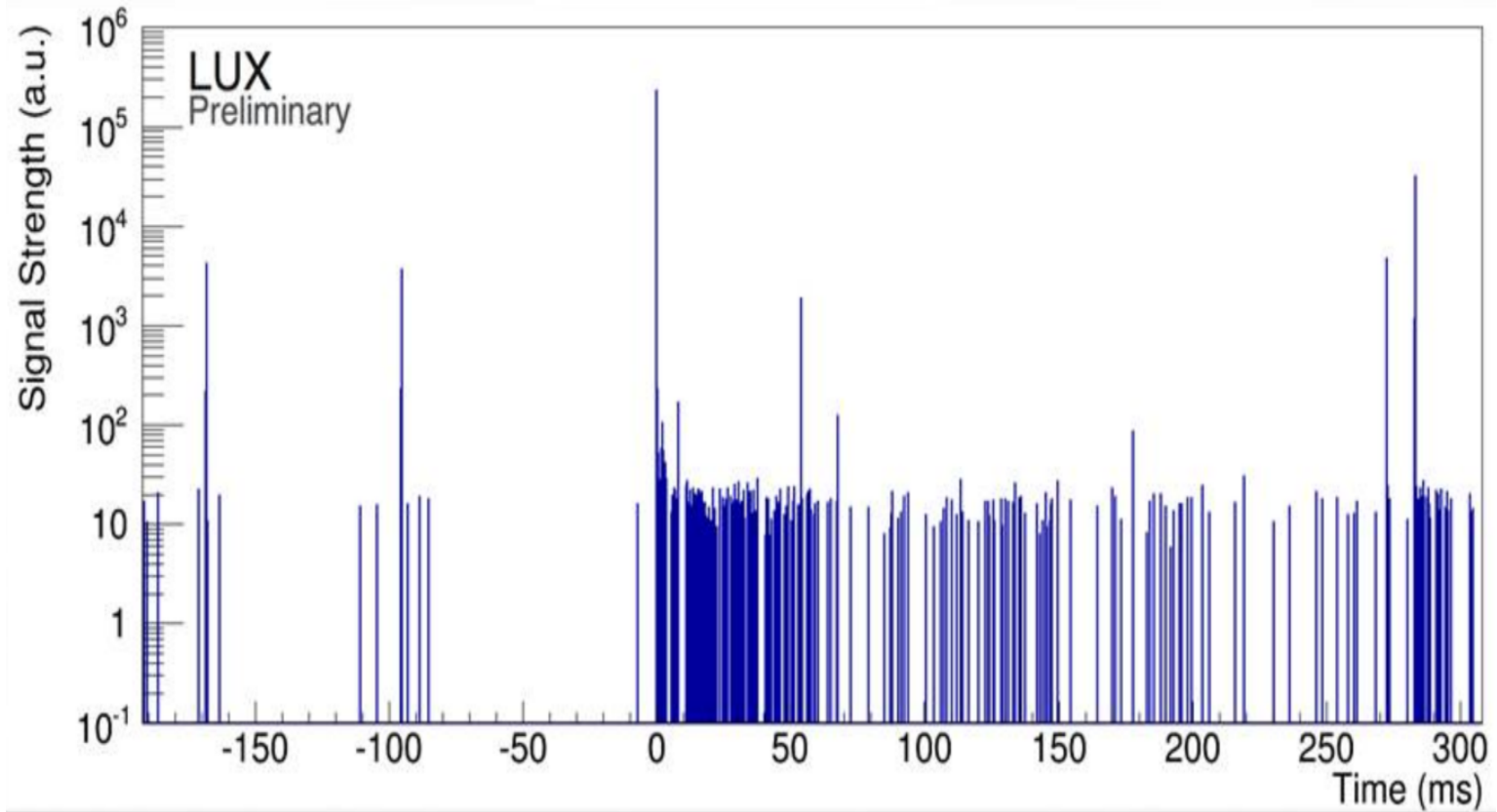
<https://arxiv.org/pdf/1605.06262.pdf>

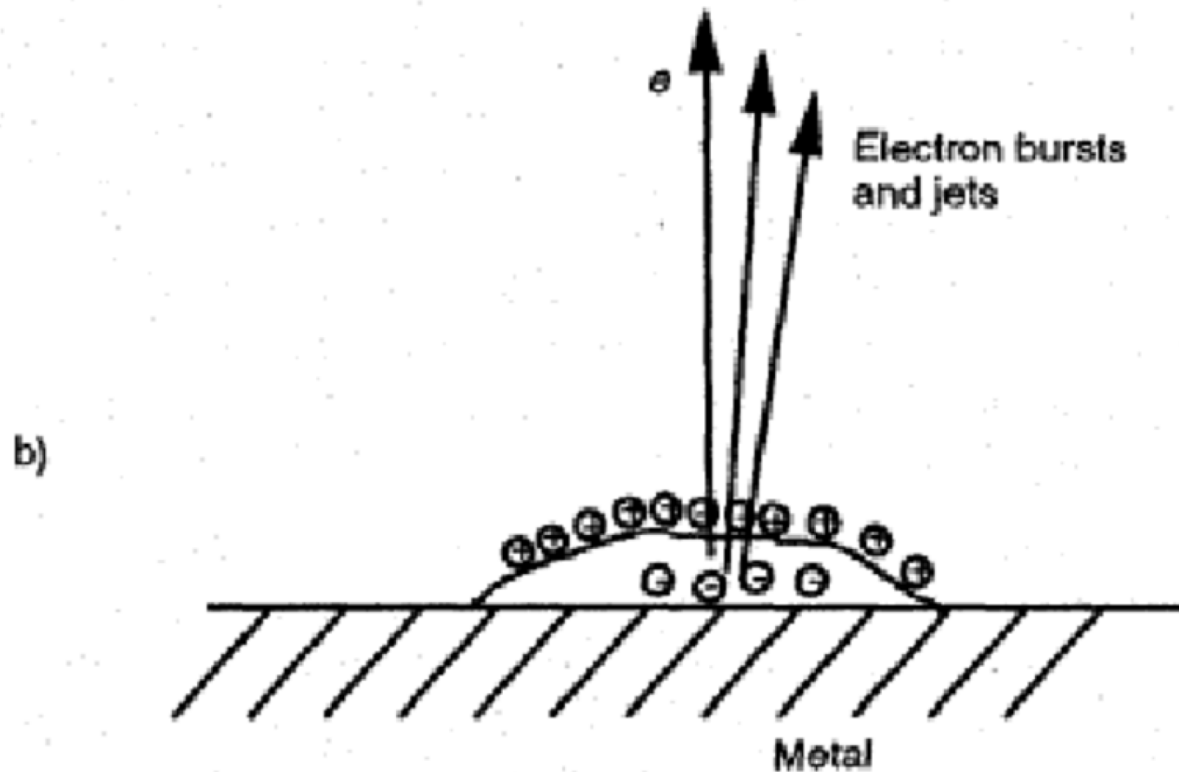
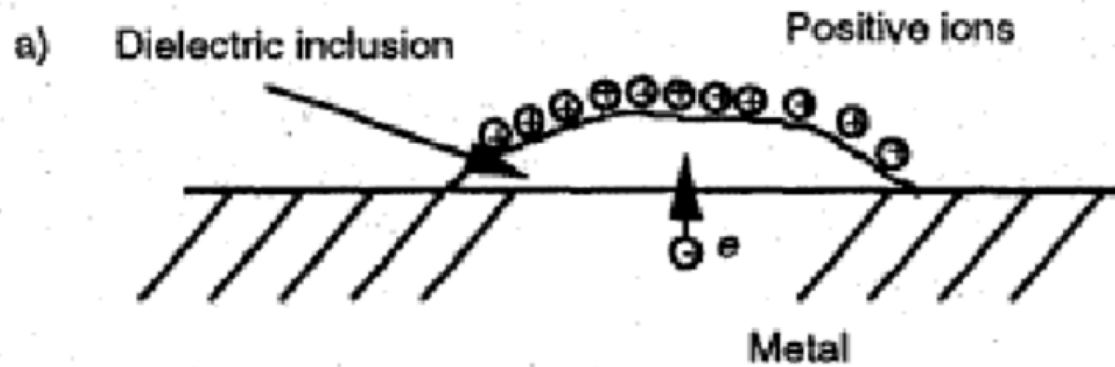
# Photoionization



<https://arxiv.org/pdf/1311.1088.pdf>

# Electron Train Background



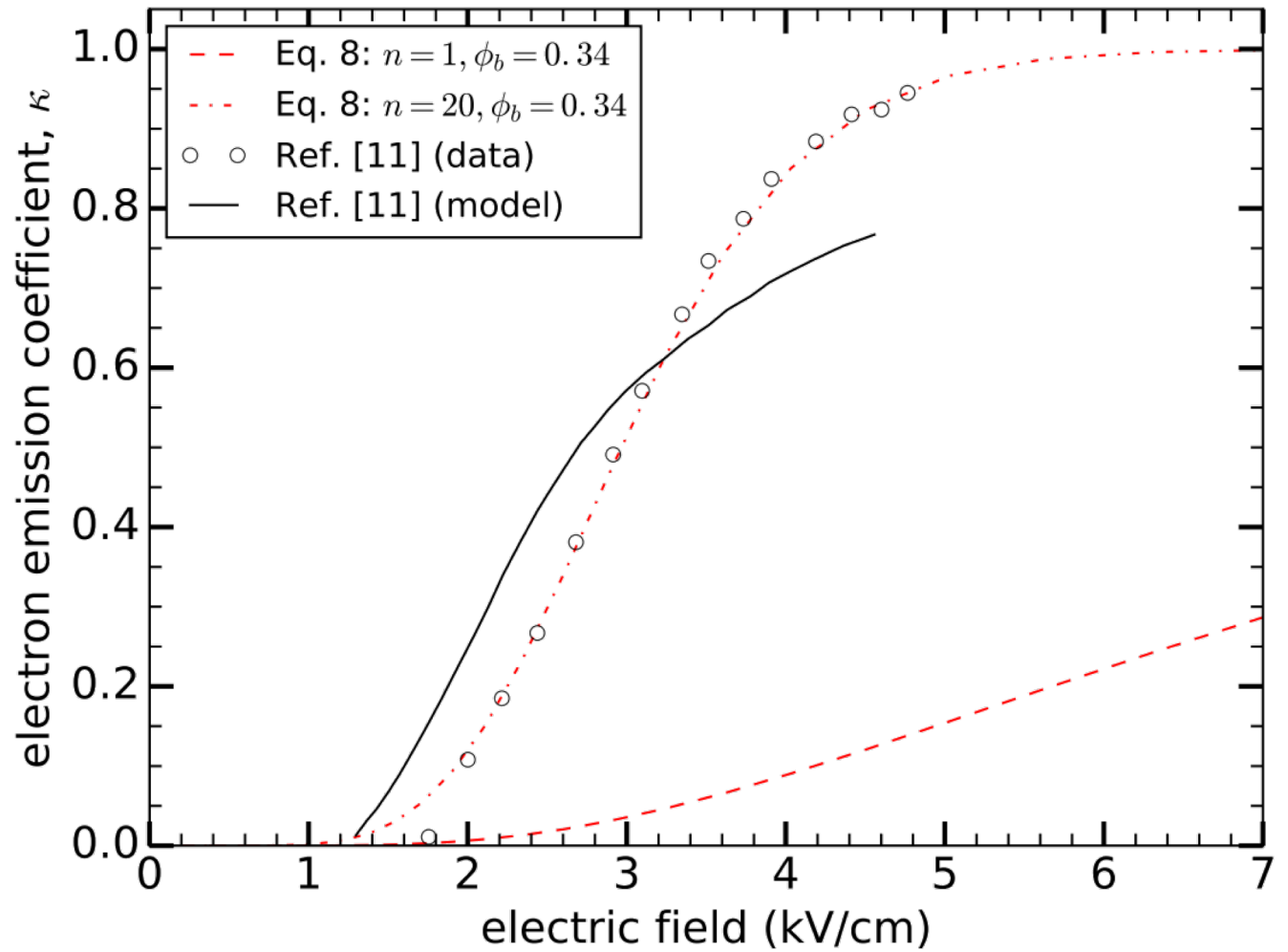


## Malter effect

Trapped positive ions on the cathode can lower the work function of the metal, making it easier to emit electrons. This may lead to few-electron bursts.



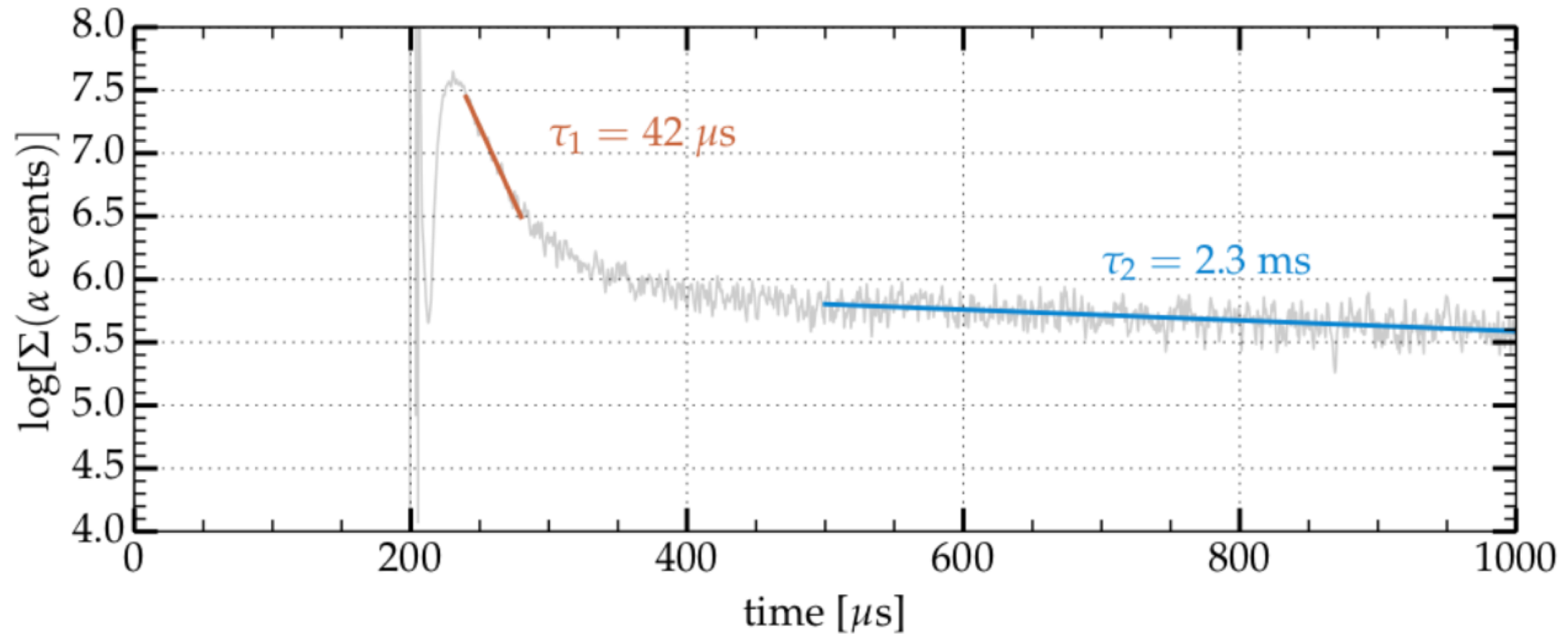
# Trapped Electrons



[http://www.jetp.ac.ru/cgi-bin/dn/e\\_055\\_05\\_0860.pdf](http://www.jetp.ac.ru/cgi-bin/dn/e_055_05_0860.pdf) (Ref. 11)

<https://arxiv.org/pdf/1702.04805.pdf>

# Long lived excited states



<https://arxiv.org/pdf/1711.07025.pdf>

# My Work

1

Determining the decay constant(s) of the electron trains

2

Determining electron efficiency by analyzing data with different electric fields

# Conclusion

- Electron trains could be caused by:
  - Photoionization
  - Trapped electrons
  - Malter effect
  - Long lived excited states
- By eliminating these electron trains we can use noble element detectors to probe for sub  $\text{GeV}/c^2$  dark matter particles!



# Back up slides

# Equations to slide 9

$$\phi_b = \frac{e^2}{8\pi\epsilon_0 z} \frac{\epsilon - 1}{\epsilon + 1}.$$

Schottky barrier – aka work function. As an electron approaches a dielectric boundary that is held at a constant potential, the force due to its image charge results in an energy barrier.

$\epsilon$  => dielectric constant of boundary (1.5-2 for xenon)

$z$  => characteristic dimension of the order of the lattice constant (~5 angstrom)

$$\Delta\phi_b = e \left( \frac{eE}{4\pi\epsilon_0 z} \frac{\epsilon - 1}{\epsilon + 1} \right)^{1/2}$$

The external field  $E$  does two things with respect to electron emission: it increases the energy of the drifting electrons, and it lowers the height of the barrier by an amount equal to

$$\kappa = \frac{\int_{\phi_b - \Delta\phi_b}^{\infty} \epsilon^{1/2} f_0(\epsilon) d\epsilon}{\int_0^{\infty} \epsilon^{1/2} f_0(\epsilon) d\epsilon},$$

Electron emission efficiency. the factor  $\epsilon^{1/2}$  serves to select electrons whose velocity has a component directed toward the barrier.

$f_0$  is the electron energy distribution

$\epsilon \rightarrow$  energy

$$\kappa_n = 1 - (1 - \kappa)^n.$$

Electron emission efficiency after  $n$  tries